

Two-Dimensional Violet Phosphorus P_{11} : A Large Band Gap Phosphorus Allotrope

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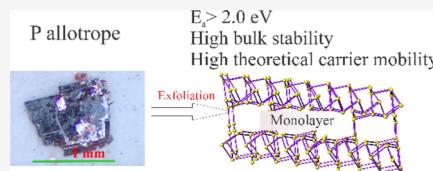
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ABSTRACT: The discovery of novel large band gap two-dimensional (2D) materials with good stability and high carrier mobility will innovate the next generation of electronics and optoelectronics. A new allotrope of 2D violet phosphorus P_{11} was synthesized via a salt flux method in the presence of bismuth. Millimeter-sized crystals of violet- P_{11} were collected after removing the salt flux with DI water. From single-crystal X-ray diffraction, the crystal structure of violet- P_{11} was determined to be in the monoclinic space group $C2/c$ (no. 15) with unit cell parameters of $a = 9.166(6)$ Å, $b = 9.121(6)$ Å, $c = 21.803(14)$ Å, $\beta = 97.638(17)^\circ$, and a unit cell volume of $1807(2)$ Å³. The structure differences between violet- P_{11} , violet- P_{21} , and fibrous- P_{21} are discussed. The violet- P_{11} crystals can be mechanically exfoliated down to a few layers (~6 nm). Photoluminescence and Raman measurements reveal the thickness-dependent nature of violet- P_{11} , and exfoliated violet- P_{11} flakes were stable in ambient air for at least 1 h, exhibiting moderate ambient stability. The bulk violet- P_{11} crystals exhibit excellent stability, being stable in ambient air for many days. The optical band gap of violet- P_{11} bulk crystals is 2.0(1) eV measured by UV–Vis and electron energy-loss spectroscopy measurements, in agreement with density functional theory calculations which predict that violet- P_{11} is a direct band gap semiconductor with band gaps of 1.8 and 1.9 eV for bulk and monolayer, respectively, and with a high carrier mobility. This band gap is the largest among the known single-element 2D layered bulk crystals and thus attractive for various optoelectronic devices.



INTRODUCTION

Driven by application needs in next-generation electronics and optoelectronics, extensive efforts have been dedicated to studying and discovering wide band gap two-dimensional (2D) layered materials with band gaps >2 eV.^{1–16} 2D layered materials can be catalogued into two groups: elemental and compound 2D materials.^{17–22} The elemental 2D materials, composed of single elements and simple bonding structures, may be more suitable for device applications compared to compound 2D materials.^{17–22} The largest band gap of elemental 2D materials is in the single-layered black phosphorus with a band gap of ~2.3 eV;^{23–25} however, applications of single-layered black phosphorus are impeded by its low ambient stability.^{26–34} Exploring new elemental 2D compounds with band gap ≥ 2.0 eV, high stability, and high mobility is thus essential for developing next-generation electronics and optoelectronics.

The allotropes of phosphorus remain exciting for decades due to the continual discovery of new 2D materials.^{35–52} Experiments and theory calculations continue to discover and predict more 2D materials.^{35–52} In this work, a new phosphorus allotrope violet- P_{11} was grown as large crystals by a novel method that combines high-temperature salt flux and bismuth metal. The newly discovered layered violet phosphorus P_{11} has a band gap of 2.0(1) eV for bulk crystals, coupled with good bulk stability and high predicted electron

mobility (1307.32 cm² V^{−1} s^{−1}). The crystal structure of violet- P_{11} was determined by a combination of synchrotron powder X-ray diffraction (PXRD), single-crystal XRD, and scanning transmission electron microscopy (STEM). The crystal structure differences between the known allotropes of phosphorus, violet- P_{11} , violet- P_{21} , and fibrous- P_{21} , are discussed. Very thin, few-layered violet- P_{11} crystals were obtained by mechanical exfoliation and found to be stable upon exposure to air for at least 1 h. The bulk violet- P_{11} crystals exhibit excellent stability, being stable in ambient air for many days. The thickness-dependent characteristics of violet- P_{11} crystals were revealed by the photoluminescence (PL) and Raman measurements. Density functional theory (DFT) calculations were employed to study the electronic structures of violet- P_{11} crystals. The excellent bulk air stability, easy growth of large crystals, and high predicted carrier mobility coupled with its large band gap of violet- P_{11} compared with black phosphorus make violet- P_{11} a potential candidate for future optoelectronic applications.

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■ EXPERIMENTAL DETAILS

Synthesis and Crystal Growth. Starting materials were handled in an argon-filled glovebox with O₂ levels below 1 ppm. All starting materials were of commercial grade and used without further purification: Bi pieces (Alfa Aesar, 99.99%), red P powder (Alfa Aesar, 99+%), NaCl (Alfa Aesar, 99.9%), KCl (Sigma, 99.5%), and AlCl₃ (Alfa Aesar, 99.9%). Red crystals of violet-P₁₁ were grown in the salt flux AlCl₃/KCl/NaCl (molar ratio of 0.601/0.141/0.258), which melts around 386 K. A total of 0.5 g of Bi/P molar ratio = 1:1 elements were mixed with 0.5 g salt flux. The mixtures were sealed into carbonized silica tubes. The sealed quartz tubes were heated from room temperature to 773 K within 1/2 h, annealed at this temperature for 120 h, and then the furnace was shut off. The salt flux was removed by DI water. The crystals show a red color with a significant layered nature, as shown in Figure 1a. The Bi elements

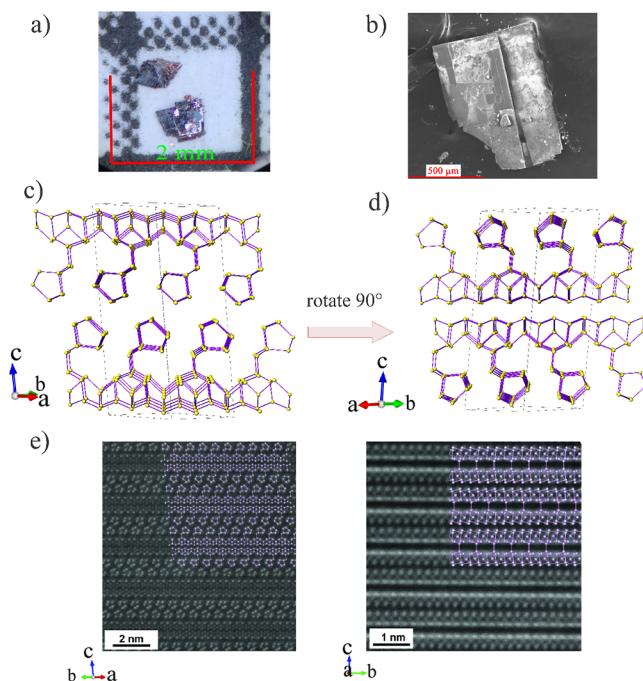


Figure 1. (a) Optical micrograph of violet-P₁₁ crystals; (b) SEM image of a violet-P₁₁ crystal; (c,d) crystal structure of violet-P₁₁ viewed along two directions; and (e) high-angle annular dark field (HAADF) STEM image of a violet-P₁₁ crystal viewed along two directions with scale bars of 2 nm (e left) and 1 nm (e right).

seem to act as catalysts during the crystal growth process. No crystals were found in the reaction when Bi was absent. Increasing the total mass of raw materials and flux and putting them in a larger quartz tube can result in higher yields. The synthesis yield can also be increased by heating reaction vessels twice using the same temperature profile. The elemental analysis using energy-dispersive X-ray (EDX) spectroscopy confirmed the absence of Bi elements in violet-P₁₁ crystals (Table S1).

Characterizations. *Single-Crystal XRD.* The crystal data were collected on a Bruker SMART APEX-II diffractometer equipped with a CCD area detector and graphite-monochromated Mo K α radiation ($\lambda = 0.71073$ Å) under a nitrogen gas atmosphere at 100 K. Crystallographic data for violet-P₁₁ have been deposited to the Cambridge Crystallographic Data Centre, CCDC, 12 Union Road, Cambridge CB21EZ, UK. Copies of the data can be obtained free of charge by quoting the depository numbers CCDC-2208167.

Powder X-ray Diffraction, Scanning Electron Microscopy, and Energy-Dispersive X-ray Spectroscopy Analysis. Lab PXRD analysis was performed at room temperature using a Rigaku Miniflex VI diffractometer employing Cu K α radiation. High-resolution PXRD experiments were carried out at the 11bm beamline at the Advanced

Photon Source at Argonne National Laboratory. Amorphous SiO₂ was mixed with violet-P₁₁ to reduce its layered orientation during the PXRD measurement. Elemental analysis was carried out on a Hitachi S4100T scanning electron microscope with EDX microanalysis (Oxford INCA Energy).

UV–Vis Measurements. Diffuse-reflectance spectra were collected at room temperature by a PERSEE-T8DCS UV–Vis spectrophotometer equipped with an integration sphere in the wavelength range of 230–850 nm.

Scanning Transmission Electron Microscopy. Bulk crystals were mechanically exfoliated into few-layered samples using Scotch tape and transferred to SiO₂/Si substrates. STEM samples were prepared using a focused ion beam (Thermo Fisher Scientific Helios) and the standard lift-out procedure. Final thinning was performed with 5 kV Ga ions. STEM images were taken on a Thermo Fisher Scientific Spectra 300 TEM at 300 kV. Simulated STEM images were generated using Computem.

Electron Energy-Loss Spectroscopy Measurements. Low-loss electron energy-loss spectroscopy (EELS) measurements to determine the band gap were performed on a monochromated, aberration-corrected TFS Titan Themis 300 X-FEG, with a Gatan GIF Tridiem energy filter. The measurements were performed with an accelerating voltage of 60 kV, a probe convergence semiangle of 60 mrad, and an EELS collection semiangle of 40 mrad. From vacuum zero-loss peak (ZLP) measurements, the ZLP full width at half-maximum (fwhm), full width at tenth-maximum, and full width at a hundredth-maximum were 0.22, 0.45, and 0.90 eV, respectively. Measurements were performed on an exfoliated flake and transferred to a SiN STEM grid using a PDMS stamp. The presented EELS measurements all come from the same flake, which exhibited a thickness gradient in the studied region, ranging from 0.2 to 0.69 inelastic mean free paths. Using ~45 nm as the inelastic mean free path for phosphorus at 60 kV, the thickness ranged from 9 to 31 nm (vide infra).

Photoluminescence. PL measurements of exfoliated flakes were carried out using a HORIBA LabRAM HR Evolution under an excitation of 532 nm with a power of 1 mW and collected by a Synapse spectrometer with a grating of 600 grooves/mm under ambient conditions.

Raman Spectroscopy. Raman spectra of exfoliated flakes were collected with a HORIBA LabRAM HR Evolution system under an excitation of 633 nm at 1 mW and collected by a spectrometer with a grating of 1800 grooves/mm under ambient conditions.

Atomic Force Microscopy. Height profiles of few-layered exfoliated crystals were obtained using a Cypher ES microscope from Asylum Research. Atomic force microscopy (AFM) images and three-dimensional (3D) renderings of few-layered exfoliated crystals were acquired using a Veeco Icon Atomic Force Microscope in tapping mode using a NanoWorld Arrow NC AFM probe at a scan rate of 2 Hz at 256 pixels/line. All images were performed under ambient conditions.

Device Fabrication. Few-layered flakes transferred on the SiO₂/Si wafers were spin coated with layers of ebeam-resist and written with electron beam lithography (Nabity NPGS, Helios G4 FIB-SEM) at a voltage of 30 kV and a current of 1.6 nA. The written pattern was etched with argon plasma at 50 mW for 10 min and in situ deposited with 15 nm Cr and 200 nm of Au using a ultrahigh vacuum electron beam evaporator.

Field-Effect Transistor Measurements and Mobility Calculation. Back-gated field-effect transistor (FET) transfer curves of the devices were measured in air using the Agilent Technologies B1500A semiconductor device analyzer. The carrier mobility was calculated

based on the transfer curve of the device using the equation:
$$\left(\frac{\partial I_D}{\partial V_{GS}}\right)_L = \frac{\left(\frac{\partial I_D}{\partial V_{GS}}\right)_L}{V_{DS}C_{ox}W}$$
, where $\left(\frac{\partial I_D}{\partial V_{GS}}\right)_L$ is the maximum transconductance and C_{ox} is the gate capacitance of 285 nm thick SiO₂ with a value of 1.2×10^{-8} F/cm²; L and W are the length and width of the conducting channel, respectively.

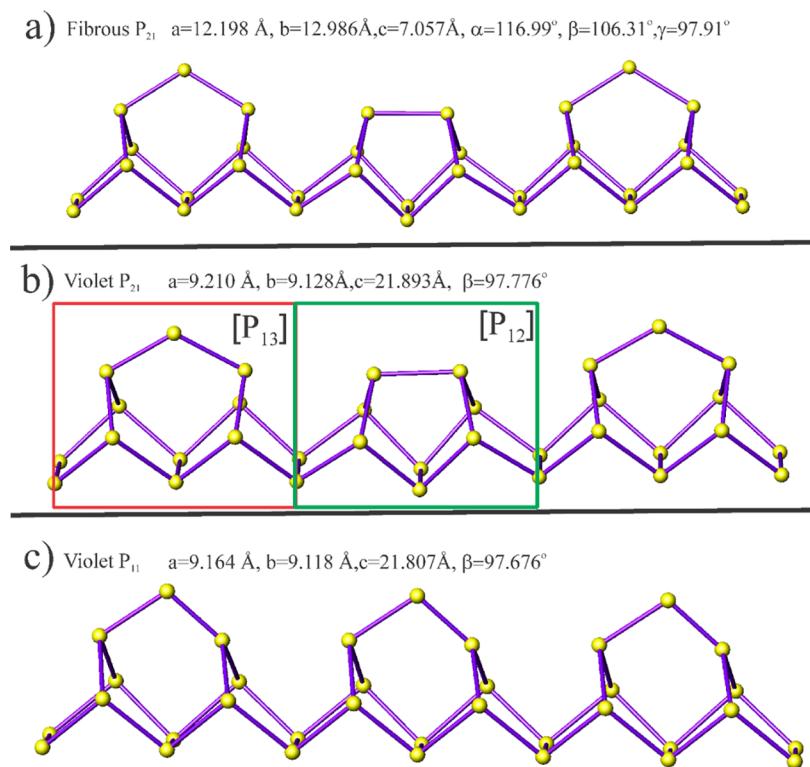


Figure 2. Detailed views of 1D structural fragment $[P_5]$ chain of (a) fibrous P_{21} ,³⁵ (b) violet P_{21} ,⁵² and (c) this work's violet- P_{11} . P atoms are presented in yellow color; P–P bonds are presented by purple sticks. The $[P_{13}]$ units and $[P_{12}]$ units are highlighted by red and green squares, respectively.

DFT Calculations. The first-principles calculations were performed within the framework of DFT using the Vienna Ab initio Simulation Package (VASP) code.^{53–55} Generalized gradient approximation within the Perdew–Burke–Ernzerhof (PBE) method was employed to describe exchange–correlation potential.⁵⁶ A plane-wave basis set along with an energy cutoff of 500 eV was used to describe electron wavefunctions. The interactions between electrons and nuclei were described within the projector-augmented wave method.⁵⁵ The Brillouin zone was sampled using the mesh sizes of $5 \times 5 \times 1$ for 2D systems and $4 \times 4 \times 2$ for 3D bulk in the Γ -centered Monkhorst–Pack scheme.⁵⁷ The convergence criteria for electronic and ionic relaxations were set as 10^{-6} eV and 0.01 eV/Å, respectively. Moreover, a 20 Å vacuum space along the z -direction was added to model the characteristics of 2D monolayers. Particularly, the DFT-D3 method was employed to describe the van der Waals interactions.⁵⁸ Electronic band structures were also obtained by the Heyd–Scuseria–Ernzerhof (HSE06) screened hybrid functional.⁵⁹ The phonon spectrum was calculated using the finite displacement method within a $3 \times 3 \times 1$ supercell as implemented in the PHONOPY package.⁶⁰ Ab initio molecular dynamics (AIMD) simulations are performed on a $2 \times 2 \times 1$ supercell within the canonical ensemble (NVT) using a Nosé–Hoover thermostat.^{61,62}

Carrier Mobility Calculations. In 2D monolayers, the carrier mobility is calculated by the deformation potential (DP) theory,⁶³ which is described as $\mu = \frac{e\hbar^3 C_{2D}}{k_B T m^* m_d E_1^2}$, where \hbar , k_B , and T represent Planck's constant divided by 2π , Boltzmann constant, and temperature, respectively.^{64–66} The term C_{2D} is the elastic modulus of a uniformly deformed 2D crystal. m^* is the effective mass of the carrier in the transport direction defined as $m^* = \pm \hbar^2 \left(\frac{d^2 E_k}{dk^2} \right)^{-1}$, where k is the wave vector, E_k is the energy related to the wave vector k ; and m_d is the average effective mass determined by $m_d = \sqrt{m_x^* m_y^*}$. The term E_1 represents the DP composed of the conduction band minimum (CBM) for electrons and valence band maximum (VBM) for holes, as

determined by $E_1 = \Delta E_i / (\Delta l / l_0)$, where ΔE_i is the energy shift of the band edge of CBM or VBM vs. the lattice deformation $\Delta l / l_0$. These data are calculated with strains varied from -0.01 to 0.01 in a step of 0.005 . All the mobilities have been calculated at 300 K.

RESULTS AND DISCUSSION

Crystal Growth and Crystal Structure. The millimeter-sized crystals of violet- P_{11} were grown in a salt flux and are shown in Figure 1a. The bulk violet- P_{11} crystals exhibit extraordinarily high ambient stability (vide infra). After water treatments, there were no detectable changes found on the crystals, which were verified by scanning electron microscopy (SEM) and STEM (Figure 1b, Table S1, and Figure S1) and PXRD (Figure S2). Single-crystal XRD revealed that violet- P_{11} crystallizes in the monoclinic space group $C2/c$ (no. 15) with unit cell parameters of $a = 9.166(6)$ Å, $b = 9.121(6)$ Å, $c = 21.803(14)$ Å, $\beta = 97.638(17)$ °, and a unit cell volume of $1807(2)$ Å³. The Wyckoff sequence of violet- P_{11} is g^{11} with Pearson symbol $oP72$. The crystal structure of violet- P_{11} viewed along two different directions is presented in Figure 1c,d. The selected crystal data and structure refinement parameters for violet- P_{11} are presented in Table S2. The refined atomic coordinates and selected important interatomic distances of violet- P_{11} are summarized in Tables S3 and S4, respectively.

There are 11 distinct P atoms in the asymmetric unit cell of violet- P_{11} with full occupancy. The violet- P_{11} structure is constructed by 2D $[P_{11}]$ slabs. The 2D $[P_{11}]$ slabs are made by two one-dimensional (1D) $[P_5]$ chains that are perpendicular to each other and linked by the bridging P atoms. The crystal structure of violet- P_{11} determined from single-crystal XRD is also supported by STEM images (Figure 1e) and property

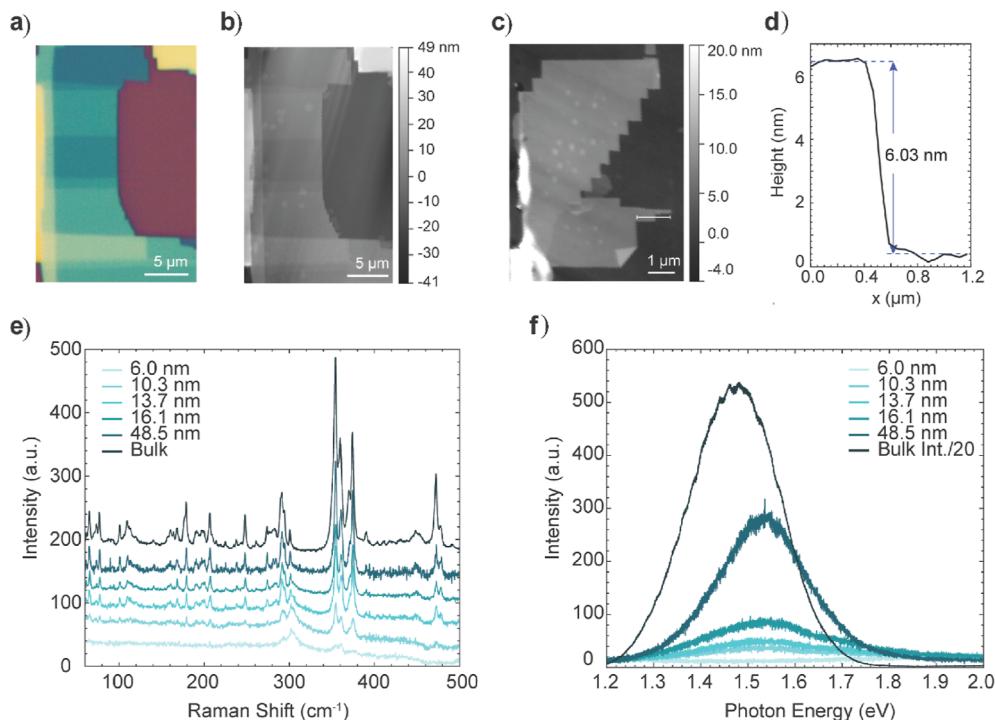


Figure 3. Thickness-dependent Raman and PL emission spectra of violet-P₁₁. (a,b) Optical micrograph (a) and AFM height map (b) of a multilayered exfoliated flake. (c) AFM height map of a thin violet-P₁₁ flake. (d) Height trace of the flake along the marked white solid line in (c). (e) Thickness-dependent Raman spectra of violet-P₁₁ from trilayer to bulk under the excitation of a 633 nm laser. (f) Thickness-dependent PL emission spectra of violet-P₁₁ from trilayer to bulk under the excitation of a 532 nm laser.

measurements (vide infra). The detailed view of the 1D [P₅] chain is shown in Figure 2c. The 1D [P₅] chain is made of interconnected P₅ pentagon rings sharing three P atoms. A similar connectivity of P₅ pentagon rings was also discovered in La₇Zn₂P₁₁,⁶⁷ black P,⁶⁸ violet-P₂₁,⁵² and fibrous-P₂₁.³⁵ The covalent radius for P is 1.07 Å. The P–P distances in violet-P₁₁ fall into the range of 1.95(2) Å–2.266(12) Å (Table S4), which is typical for homoatomic P–P bond distances such as in black P (2.224 Å),⁶⁸ violet-P₂₁ (2.186–2.285 Å),⁵² fibrous-P₂₁ (2.178–2.299 Å),³⁵ La₂Ba₆Cu₁₆P₃₀ (2.071–2.428 Å),⁶⁹ K₂BaP₂S₆ (2.223(4) Å),⁷⁰ Ba₈Cu₁₆P₃₀ (2.159–2.299 Å),⁷¹ La₇Zn₂P₁₁ (2.207(7) Å),⁶⁷ La₄Zn₇P₁₀ (2.151(8) Å),⁷² and so forth.

At first glance, the structure of violet-P₁₁ is similar to the known fibrous-P₂₁ and violet-P₂₁. The structure comparison of the three phosphorus allotropes is shown in Figure S3, and a detailed analysis verifies the structure differences among the three phosphorus allotropes. The fibrous-P₂₁ is constructed by isolated [P₂₁] chains, while violet-P₂₁ and violet-P₁₁ are built by 2D phosphorus layers. The unitcell parameters of violet-P₁₁ are close to those of violet-P₂₁ (Figure 2). However, the structure symmetry of violet-P₁₁ [C₂/c (no. 15)] is higher than that of violet-P₂₁ [P₂/n (no. 13)]. There are 21 distinct P atoms in the asymmetric unitcell of violet-P₂₁ with full occupancy, while violet-P₁₁ has only 11 distinct P atoms in its asymmetric unitcell. All three allotropes are made by [P₅] 1D chains. The detailed view of [P₅] 1D chains of the three phosphorus allotropes is shown in Figure 2. As we can see, violet-P₂₁ has a [P₅] 1D chain identical to fibrous-P₂₁. The [P₅] 1D chain in violet-P₂₁ and fibrous-P₂₁ is alternatively linked by [P₁₃] units and [P₁₂] units. The [P₁₃] units are constructed by four P₅ pentagon rings with two pentagon rings linked by a bridging P atom. The bridging P atoms also connect two neighboring [P₅]

chains to form 2D layers in the violet-P₂₁ or 1D chains in the fibrous-P₂₁. The [P₁₂] units are built by four P₅ pentagon rings with two pentagon rings linked by two vertex P atoms. In violet-P₁₁, there are only [P₁₃] units repeatedly interconnected through the crystal structure (Figure 2c). Moreover, the PXRD (Figure S2), cross-sectional STEM data analysis (Figure S4), Raman spectroscopy measurements, DFT calculations, and UV–Vis spectrum measurements all confirmed the structure difference between the violet-P₂₁ and the violet-P₁₁ (Table S5 and vide infra).

Layer-Dependent Optical Properties. Guided by the “2D” layered nature of the violet-P₁₁, we mechanically exfoliated the bulk millimeter-sized crystals down to multilayered micrometer-sized flakes, as displayed in Figure 3a,b. These exfoliated flakes have thicknesses ranging from 10 to 50 nm, differing in their color and optical contrast. The thinnest flake we achieved has a thickness of 6.0 nm, corresponding to three units of violet-P₁₁ stacking slabs (Figure 3c,d). We note that the exfoliated flakes shown in Figure 3a,c possess indented edges with an angle of 90°, reflecting the monoclinic nature of the violet-P₁₁ crystals.

As the flake thickness is reduced with exfoliation, optical properties like Raman spectra and PL exhibit strong thickness-dependent characteristics, as shown in Figure 3e,f, respectively. We measured the Raman spectra of the bulk crystal and exfoliated flakes down to a trilayer flake. Due to the large number of phosphorus atoms inside a violet-P₁₁ unit cell, the number of active Raman modes is large. To simplify the discussion, we will divide the Raman modes into two groups (groups I and II), as referred in the Raman investigations on Hittorf's red phosphorus flake and amorphous red phosphorus.⁷³ Group I includes Raman modes from 50 to 140 cm⁻¹, where interlayer vibration modes are populated due to their

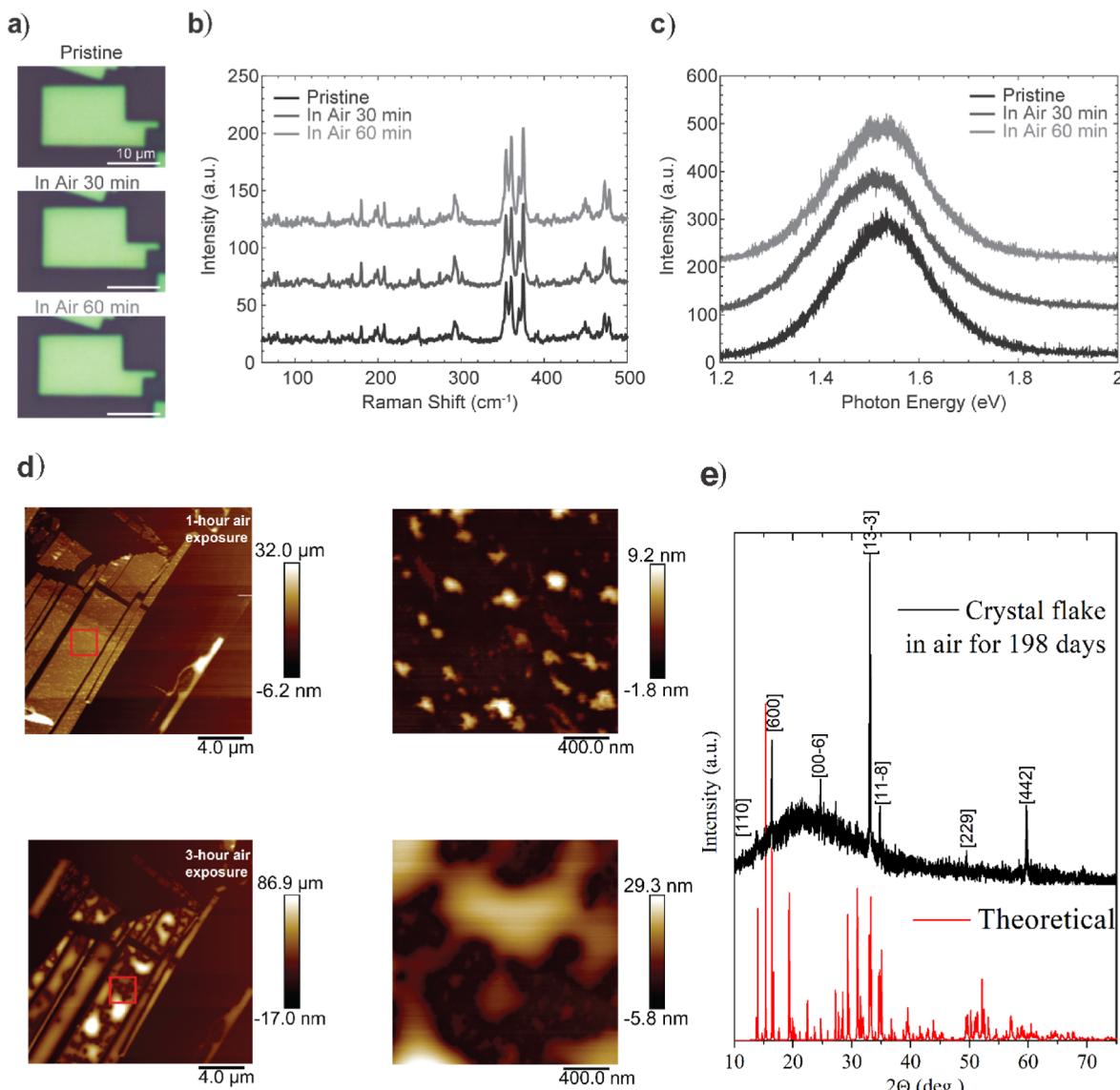


Figure 4. Optical images (a), Raman spectra (b), and PL spectra (c) of an exfoliated violet-P₁₁ flake as a function of air exposure time, spanning the freshly exfoliated pristine state, in air for 30 min and in air for 60 min. (d) AFM height map of thin violet-P₁₁ flakes after 1 h (top left) and 3 h (bottom left) of air exposure; (right images) enlarged images of the regions shown by the red squares in top left and bottom left, respectively. (e) PXRD results of a crystal flake (1.1 mm × 1.1 mm × 0.5 mm) stored in ambient air for 198 days.

large masses and small restoring forces. Group II contains the modes from 140 to 500 cm⁻¹ where most modes belong to the intralayer bending and stretching modes. These two groups of Raman modes exhibit distinct thickness-dependent characteristics. (1) The intensities of the group-I modes gradually die down from the bulk to the trilayer sample, indicating a significant reduction of interlayer vibrations as the flake thickness decreases, particularly in the case of the trilayer sample where no active interlayer vibration modes are present; (2) however, most intralayer vibration modes in group II are present regardless of the flake thinning down. For example, modes populated around 280–400 cm⁻¹ remain active even in the trilayer sample, accompanied by a noticeable peak broadening due to a reduced crystallite size.

PL, a radiative combination of photo-generated electrons and holes in semiconductors, typically reflects the nature of the electron band structure as well as the energy state of the defects. We measured the PL emission spectra of the violet-P₁₁

crystal as a function of flake thickness under the excitation of a 532 nm (2.33 eV) laser at room temperature, as summarized in Figure 3f. The bulk violet-P₁₁ crystal has a strong and broad PL response centered around 1.47 eV with an fwhm of 0.23 eV. This broad peak width strongly suggests the PL of the bulk at room temperature to be a defect-dominated emission rather than a near-edge band emission. The very broad fwhm of violet-P₁₁ crystals may originate from the defects,^{74,75} which was also observed in black-P⁷⁶ and violet-P₂₁.⁵² The weak signals of PL for thin violet-P₁₁ flakes might be due to its air instability (vide infra). Carrying out PL experiments under vacuum and cryogenic PL measurements is essential and ongoing to better understand the properties of violet-P₁₁ crystals. As the flake thickness decreases to 6.0 nm, the PL at 1.47 eV of the bulk sample undergoes a considerable intensity reduction as well as a redshift to a new center at 1.55 eV. Concurrently, a new shoulder peak centered around 1.70 eV emerges in samples with thicknesses less than 16 nm. At a

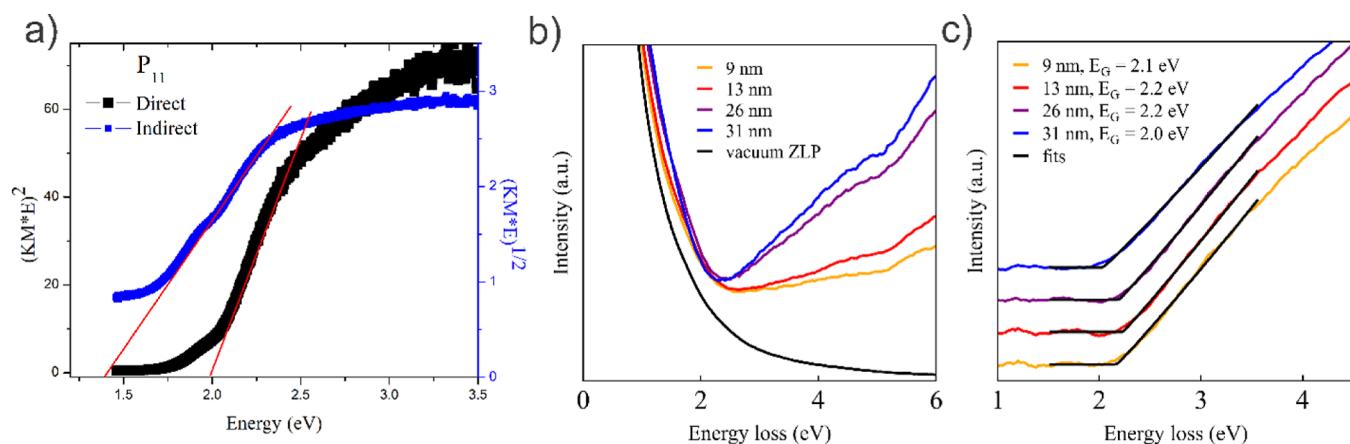


Figure 5. (a) Band gap estimation of violet-P₁₁ bulk crystals via UV–Vis spectroscopy. (b) Raw EELS data from violet-P₁₁ of various thicknesses, as well as the vacuum ZLP for reference. All data are scaled vertically based on the ZLP maximum. (c) Background-subtracted EELS data, shifted vertically for clarity. Each spectrum is fit independently. The fits are shown in black, and the fitted parameters are listed in the legend.

flake thickness of 6.0 nm, only a broad peak centered around 2.0 eV is observable with a signal-to-noise ratio of about 2.14, as shown in a rescaled plot in Figure S5. Due to a lack of time-dependent and temperature-dependent PL study within the scope of this work, we cannot identify the nature of the excitons observed in our PL emission spectra. However, this thickness-dependent PL evolution sheds some insights into the thickness-dependent electronic band structure of violet-P₁₁. (1) Since all violet-P₁₁ samples have PL response regardless of thickness, the direct band gap of violet-P₁₁ crystals from bulk down to 6 nm is less than the excitation laser energy at 2.33 eV. (2) There are multiple excitation states present in the gap between the conduction band and the valence band of violet-P₁₁ with varying quantum yields, as evidenced by the multipeak characteristics of PL in samples with a thickness from 10 to 16 nm. (3) The significant increase of PL intensity in bulk as compared to that of a few-layered sample can be attributed to either a reduction of band gap in the bulk or a switch from indirect band gap to direct band gap as the thickness increases from the nanometer to millimeter scale.

Extraordinary Ambient Stabilities for Bulk Violet-P₁₁. The stability of a nanomaterial under ambient conditions is critical to its performance for applications in electronic and optoelectronic devices. The air stability of phosphorus allotropes is challenging due to the presence of lone pairs at the surface,^{76–80} which gets more pronounced in thinner flakes due to increased surface to volume ratios.^{76–80} Hence, in this work, the ambient stability of bulk crystals and thin flakes of violet-P₁₁ were studied carefully via AFM characterization, Raman spectroscopy, optical imaging, PL spectra, SEM, TEM, TEM–EDS quantification, PXRD, and AIMD simulations as a function of air exposure time (Figures 4 and S6–S12 and Table S6). The exfoliated violet-P₁₁ flake exhibited a moderate stability against air exposure, in which no observable degradation was detected after exposure to air for 1 h. Thus, the violet-P₁₁ thin flakes are stable in ambient air within a 1 h period. As demonstrated in Figure 4a, a mechanically exfoliated flake on a SiO₂/Si substrate was placed in air without further treatment or protection. The color and the optical contrast of the flake remain unchanged after 1 h of air exposure. We tracked the Raman spectra of the flake throughout the 1 h of air exposure, as summarized in Figure 4b. Since Raman spectroscopy is a tool to inform the surface atomic vibration

conditions, which are sensitive to the intrinsic crystal quality and extrinsic factors like strain and doping, Raman spectroscopy can probe if any significant oxidation occurs to the violet-P₁₁ flake, which will lead to a breaking of atomic bonds and a vanishing of the original Raman vibration modes. Strikingly, the Raman spectrum of the violet-P₁₁ flake collected after 1 h of air exposure is almost identical to that of the freshly exfoliated one. There is no obvious degradation of peak intensity and no emergence of new Raman modes within 1 h of air exposure. Similar air stability is found in the time-dependent PL in Figure 4c. The PL emission spectrum does not have any obvious changes in the shape, intensity, and position, as indicated in the peak fitting result summarized in Figure S6. The selected area electron diffraction also did not detect any noticeable degradation of crystallinity after 90 min of air exposure (Figure S7a–c). EELS (sensitive to bonding) analysis shows that the P L_{2,3} edge does not show any obvious changes after 90 min of air exposure (Figure S7e). When exposed to ambient air longer, surface degradation did occur to thin violet-P₁₁ flakes. As shown in Figure 4d, the AFM imaging showed obvious surface degradation after 3 h of air exposure, which are supported by the AFM height maps (Figure S8), optical images (Figure S9), and STEM–EDS collection on a surface of a 57 nm thick violet-P₁₁ crystal (Figure S7d).

The mechanism of surface reactions between the violet-P₁₁ single layer and oxygen is an important question for understanding the degradation of violet-P₁₁ crystals. To explore the ambient stability of monolayer violet-P₁₁ under the O₂ environment, we performed AIMD at room temperature (300 K) for 5 ps (Figure S10). Our AIMD results manifest that the violet-P₁₁ single layer easily reacts with O₂, which is very similar to the case of black phosphorene.^{79,80} After 5 ps of contact, some gaseous-phase O₂ molecules dissociate into O atoms on the violet-P₁₁ surface and form the chemisorbed oxygen in the dangling or bridge configuration, as shown in Figure S10b. As shown in Figure S10a, there is a significant decrease in total energy at 3 ps, which means the occurrence of surface oxidation. Such simulation results indicate that the interaction between violet-P₁₁ and O₂ molecules is relatively strong. Thus, some air-stable passivation layers may be necessary to encapsulate the violet-P₁₁ thin layers or monolayer in devices.⁷⁸

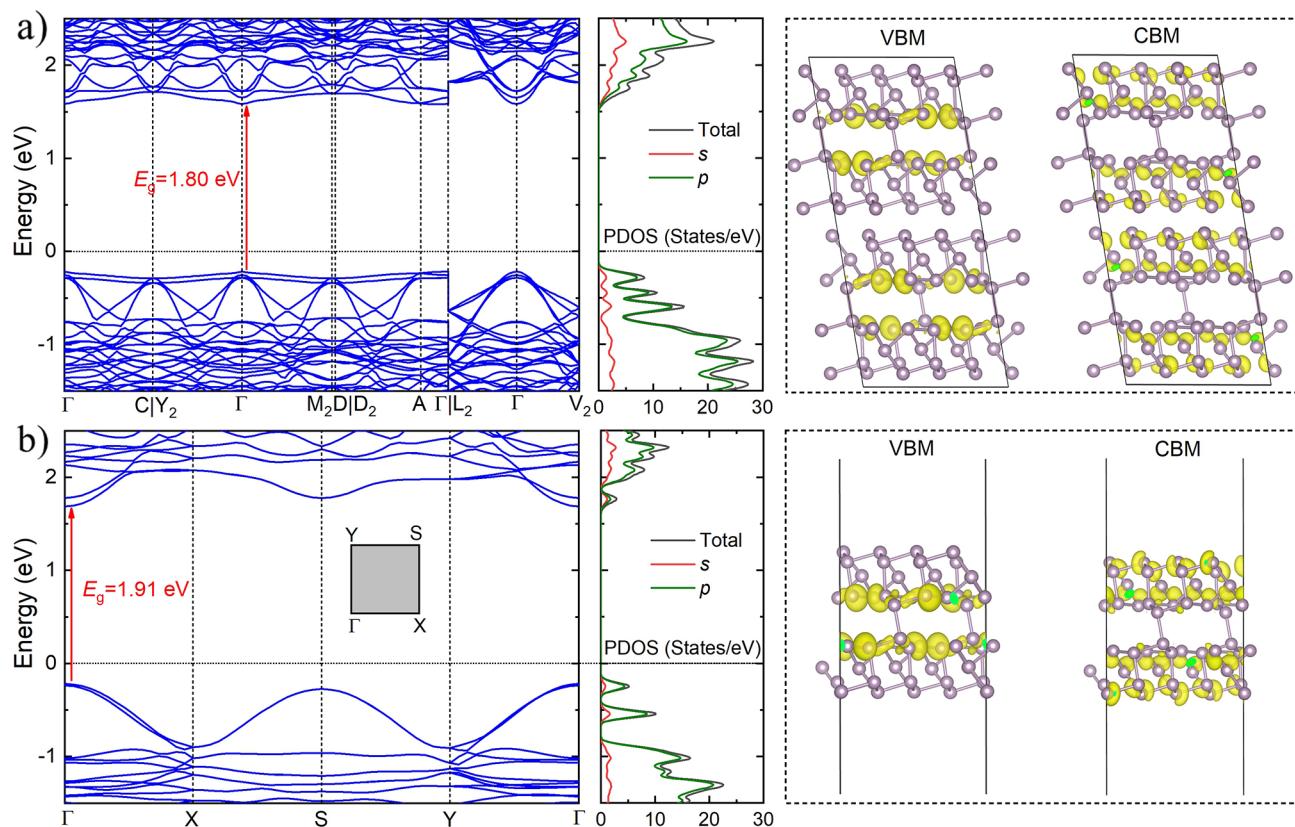


Figure 6. Band structures, the partial density of states, and electron density distribution at the VBM and the CBM of (a) bulk and (b) monolayer violet-P₁₁ based on the HSE06 functional. The Fermi level is set at 0.

The air stability increases with increasing thickness of violet-P₁₁ crystals. As summarized in Table S6, a 27 nm thick flake shows almost double the amount of oxygen than a 96 nm thick flake under the same air exposure. The SEM imaging of a thick and thin exfoliated violet-P₁₁ crystals after exposure to air for 23 days is shown in Figure S11. As shown in Figure S11, no noticeable change was found for the bulk crystals, while the thin flakes showed morphological change on the top surface. Raman spectra and optical images of a thick violet-P₁₁ crystal on a PDMS substrate are presented in Figure S12. Strong and characteristic Raman signals of violet-P₁₁ crystals were present after the sample was exposed to air for 7 days, while impurity signals did appear after exposure to air for 1 day. Another proof of the robust stability of bulk violet-P₁₁ is that all violet-P₁₁ crystals were collected after water treatment for about 30 min. A crystal flake stored in ambient air for 198 days still showed PXRD signals (Figure 4e), which indicates the presence of a crystalline phase. In conclusion, violet-P₁₁ bulk crystals exhibit extraordinary ambient stabilities. Thin flakes of violet-P₁₁ crystals can be stable in air for about 90 min.

Linear Optical Property Measurements. The large band gap of violet-P₁₁ was verified by both experimental results (Figures 5 and S13) and DFT calculation results (vide infra). The measured optical band gap of bulk violet-P₁₁ crystals is 2.0(1) eV for direct allowed transition (Figure 5a) since bulk violet-P₁₁ is predicted to be a direct band gap semiconductor (vide infra). EELS was also employed to estimate the band gap of violet-P₁₁ crystals (Figure 5b,c). From the raw EELS data (Figure 5b), all spectra are monotonically decreasing, with a slope similar to the vacuum reference, until a sharp feature at ~ 2 eV is observed. To process the data, we fit the ZLP tail with

a decaying power law function from 1 to 1.8 eV. The background-subtracted spectra are shown in Figure 5c. We then fit the data using the following equation: $I \sim (E - E_G)^n$, where I is the EELS intensity, E is the energy, E_G is the fitted band gap, and n is the fitted exponent. For $E < E_G$, I is set to 0. The fitting range was 1.5–3.5 eV. The fitting results are shown in Figure 5c. The analysis shows that the band gap (E_G) of violet-P₁₁ is around 2.1 ± 0.1 eV, which agrees with UV–Vis results. We note that for flake thicknesses ranging from 9 to 31 nm (0.2–0.69 inelastic mean free paths), the value of E_G is essentially constant, which suggests that our analysis is not influenced by Cherenkov radiation or surface effects. The experimental results agree well with our DFT calculation results (vide infra). The UV–Vis spectrum and EELS analysis coupled with DFT calculation demonstrate the large band gap nature of violet-P₁₁.

DFT Calculations. Electronic band structures of both bulk violet-P₁₁ and single-layer violet-P₁₁ are obtained by DFT calculations, which are shown in Figure 6. The bulk violet-P₁₁ is computed to be a direct band gap semiconductor with a band gap of 1.80 eV at the Γ point in the Brillouin zone. The calculated band gap of bulk violet-P₁₁ is much higher than those of the bulk violet-P₂₁ (1.42 eV),⁵² fibrous-P₂₁ (1.60 eV),⁴⁷ and bulk black-P (0.3 eV).²³ The measured optical band gap of bulk violet-P₁₁ is 2.0(1) eV for direct allowed transition (Figure 5a). Based on DFT calculation and UV–Vis results, the bulk violet-P₁₁ should be a direct band gap semiconductor with band gap of 2.0(1) eV. This large band gap of bulk violet-P₁₁ sets a new record for the band gap of layered elemental materials,^{17–25,81} which opens a window for next-generation electronics and optoelectronics. The monolayer violet-P₁₁ is

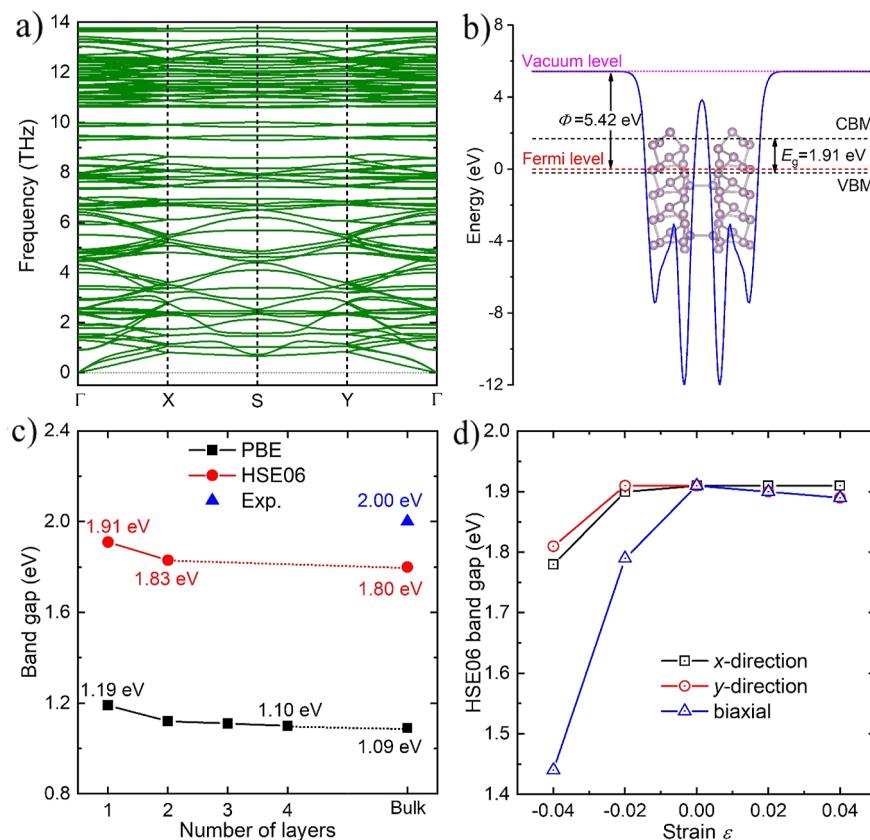


Figure 7. (a) Phonon spectrum of monolayer violet-P₁₁. (b) Electrostatic potentials and band edge alignments of monolayer violet-P₁₁. (c) Evolution of the calculated band gaps at the HSE06 and PBE levels as a function of the layer thickness of violet-P₁₁. The experimental band gap of bulk violet-P₁₁ is displayed for comparison. (d) HSE06 band gaps of monolayer violet-P₁₁ as a function of the in-plane uniaxial and biaxial strains, varying from -0.04 to 0.04.

predicted to be a direct semiconductor with a band gap of 1.91 eV at the Γ point. Interestingly, the band gap of monolayer violet-P₁₁ (1.91 eV) is comparable to that of bulk violet-P₁₁ (1.80 eV), whereas a significant difference exists between the band gaps of bulk and monolayer violet-P₂₁ (bulk: 1.42 eV and single layer: 2.54 eV)⁵² and black-P (bulk: 0.3 eV and single layer: 1.9 eV).²³ Such large band gap discrepancy does not apply to the violet-P₁₁ and fibrous-P₂₁ (bulk: 1.60 eV and single layer: 1.69 eV).⁴⁷ The phosphorus allotropes exhibit very rich chemistry, which spans from 0D isolated [P₄] clusters in white phosphorus to 2D layered allotropes. Three 2D phosphorus allotropes were experimentally discovered prior to violet P₁₁: black P, violet-P₂₁, and fibrous-P₂₁. The violet-P₁₁ has the largest bulk band gap (2.0 eV) than other three phosphorus allotropes: black-P (0.3 eV),²³ violet-P₂₁ (1.42 eV),⁵² and fibrous-P₂₁ (1.60 eV).⁴⁷

To clarify the small difference between band gaps of bulk and monolayer of violet-P₁₁, additional calculations were employed to study the distribution of real-space wavefunction. The electron density distribution at the VBM and the CBM of bulk and monolayer violet-P₁₁ is shown in Figure 6, right. The electron density distributions of monolayer violet-P₁₁ are quite similar to those of bulk violet-P₁₁. The VBM is mainly dominated by the inner P atoms of the layer, while the CBM is mainly originated from the outer P atoms of the layer. The electrostatic potentials and band edge alignments of monolayer violet-P₁₁ were also calculated and are presented in Figure 7b. The VBM and CBM positions with vacuum level corrections

are at -3.73 and -5.64 eV, respectively, and the calculated work function is 5.42 eV.

The phonon spectrum of monolayer violet-P₁₁ was calculated and is shown in Figure 7a. No appreciable negative frequency is found in the phonon spectrum, indicating that monolayer violet-P₁₁ is dynamically stable. The result of simulation agrees well with the experimental results. The thickness-dependent electronic structures of violet-P₁₁ were also studied (Figures 7c and S14). The electronic band structures of most multilayers of violet-P₁₁ were calculated at the PBE level and are shown in Figure S14. The calculated band gaps at the HSE06 and PBE levels as a function of the layer thickness (1L–4L) of violet-P₁₁ are shown in Figure 7c. Due to the small interlayer interaction and dispersion of the valence bands and the conduction bands, the band gap of violet-P₁₁ drops from 1.19 eV for the monolayer to 1.10 eV for the tetralayer, which is very close to a band gap of 1.09 eV for bulk. Actually, the layer-dependent trend of PBE band gaps is very similar to that of HSE06 band gaps. The HSE06 band gaps of monolayer and bilayer violet-P₁₁ are 1.91 and 1.83 eV, respectively, which is also close to that of bulk (1.80 eV). The potential impacts of stress on electronic structures of violet-P₁₁ were also studied via applying strains (Figures 7d and S15). The electronic structures of monolayer violet-P₁₁ under various applied uniaxial (ϵ_{xx} and ϵ_{yy}) and biaxial (ϵ_{xy}) strains of -0.04 to 0.04 are investigated, as shown in Figure S15. The band gaps as a function of applied uniaxial and biaxial strains are shown in Figure 7d. The effect of tensile strains on the electronic structure of monolayer violet-P₁₁ is very small,

manifesting as almost unchanged energy band structure and band gap under small tensile strain (Figures 7d and S15). Please note that the electronic structure of monolayer violet-P₁₁ is relatively sensitive to compressive strain, especially biaxial strain. As shown in Figure S15, the location of CBM can shift from the Γ point to $S(Y)$ point under the uniaxial compressive strain ϵ_{xx} (ϵ_{yy}) along the $x(y)$ direction, inducing the slight decrease of band gap. However, when applying the biaxial compressive strain on the monolayer violet-P₁₁, the location of CBM also moves from the Γ point to Y point and exhibits the obvious downward shift. The band gap of monolayer violet-P₁₁ reduces to 1.44 eV under a biaxial compressive strain of -0.04 .

The carrier mobilities of single-layer violet-P₁₁ are also calculated and summarized in Table 1. The single-layer violet-

Table 1. Calculated Carrier Mobility of Monolayer Violet-P₁₁

parameters	electrons	holes
m_x^*/m_0	0.25	0.35
m_y^*/m_0	0.24	0.28
E_{1x} (eV)	4.05	4.23
E_{1y} (eV)	3.77	3.93
C_x^{2D} (N/m)	51.82	51.82
C_y^{2D} (N/m)	51.29	51.29
μ_x (cm ² V ⁻¹ s ⁻¹)	1098.73	562.93
μ_y (cm ² V ⁻¹ s ⁻¹)	1307.32	806.85

P₁₁ is predicted to have extraordinarily high carrier mobilities especially for electrons [$\mu_y = 1307.32$ (cm² V⁻¹ s⁻¹)], although the FET measurements did not confirm the high mobility nature of violet-P₁₁ (*vide infra*). More detailed experiments are ongoing to investigate the carrier mobility of violet-P₁₁.

Violet-P₁₁-Based FET Attempts. We fabricated an FET on an exfoliated violet-P₁₁ flake and back gated it to measure its transfer curve, as shown in Figure S16. The exfoliated flake has a thickness of 16.6 nm according to the AFM height trace in Figure S16c, corresponding to about eight units of phosphorus slabs. The back-gated transfer curve of this FET device obtained under ambient conditions in Figure S16d exhibits a typical n-type transport characteristic and suggests the dominant carrier in violet-P₁₁ at room temperature to be electrons. We further calculated the field-effect mobility of this device to be 6×10^{-3} cm² V⁻¹ s⁻¹, which is far below the theoretically predicted value. Several intrinsic and extrinsic factors can contribute to this discrepancy between experimental data and theoretical prediction. (1) There exists a large Schottky barrier, approximately 1 eV difference between the metal work function of the contact metal Cr and violet-P₁₁'s electron affinity. A Schottky contact will severely degrade the device performance and lead to a significant underestimate of the electron mobility.⁸² (2) The device fabrication process, such as electron beam lithography at 30 keV, might have brought electron knock-on damage in the flake and this will further lead to a worsened contact with the metal electrode. (3) The electrode deposition process through the e-beam evaporator might have locally heated the sample and thus resulted in unwanted irreversible thermal damage to the violet-P₁₁ flake. (4) Surface oxidation of the exfoliated flake during device fabrication would lead to degradation of mobility. Carrying out the fabrication process under an inert atmosphere or passivation of violet-P₁₁ is important for achieving high-

quality devices and is ongoing. (5) Another worth mentioning point here is the possible overestimated theoretical carrier mobility by the deformation potentials (DP) theory, where the DP theory simply treats the scattering by longitudinal acoustic phonons and presumes the electron–phonon coupling to be isotropic.⁸³ A recent study of 2D Ti₂CO₂ MXenes demonstrated that the carrier mobility calculated by full electron–phonon coupling calculation is over 1 order of magnitude lower than that predicted by the traditional DP method.⁸³ To further study the carrier mobility of violet-P₁₁, more careful experimental studies such as fabricating devices in an inert atmosphere and theoretical studies such as fully considering electron–phonon coupling are important and ongoing.

As a new large band gap elemental 2D material, the violet-P₁₁ shows attractive properties. Electric properties of violet-P₁₁ and several 2D materials are compared in Table S7.^{25,63,84–97} As shown in Table S7, the band gap of violet-P₁₁ is comparable to many promising 2D materials such as MoS₂,^{84,85,87} WS₂,^{25,86,88} and Bi₂O₂Se.^{25,86,88,93,94} For theoretically predicted carrier mobility, violet-P₁₁ is close to WS₂^{86,88} and higher than MoS₂,^{84,85} SnSe₂,^{86,88} Bi₂O₂Se,⁹⁴ and h-BN.^{96,97} In addition, one advantage of violet-P₁₁ is its high ambient stability for bulk crystals. Another advantage of violet-P₁₁ is the easy growth as millimeter-sized crystals via a simple method, as shown in Figure S17. In contrast to conventional crystal growth methods of 2D materials such as chemical vapor deposition, molecular-beam epitaxy, and high-temperature solid-state methods, which are expensive and comprehensive, the crystal growth of violet-P₁₁ was carried out at moderately high temperature (773 K) with high yields. These millimeter-sized crystals were easily collected after a simple water wash (Figure S17), which makes future studies easy. The search for new 2D materials via theoretical studies and experiments is important and challenging.^{98–101} The discovery of violet-P₁₁ showcases the rich chemistry of phosphorus allotropes and suggests the discovery of more novel 2D materials via facile chemistry synthesis methods possible. Due to the presence of free lone pairs, the ambient stability of thin flakes of phosphorus allotropes including violet-P₁₁ is moderate. Luckily, recent studies about passivation of black P were proved to be efficient,^{26,102–104} which may guide the preparation of the device of violet-P₁₁.

CONCLUSIONS

A new 2D layered phosphorus allotrope, violet-P₁₁, was discovered by a high-temperature salt flux method. High quality and large yields of millimeter-sized violet-P₁₁ crystals, stable in water, were easily grown, which are crucial for future device fabrication. Violet-P₁₁ is also stable in ambient air after being exfoliated down to few layers for at least 1 h. PL emission spectra revealed the thickness-dependent nature and defect-dominant emission of violet-P₁₁. Violet-P₁₁ is a large band gap semiconductor of 2.0(1) eV, which is verified by UV–Vis spectra, EELS, and DFT calculations. DFT calculations predict that violet-P₁₁ is a direct band gap semiconductor with band gaps of 1.8 and 1.9 eV for bulk and monolayer, respectively, which agrees well with our experimental results. High carrier mobility is predicted for violet-P₁₁ by DFT calculations. The large band gap, facile growth of large crystals, excellent ambient stability for bulk crystals, and extraordinarily high predicted carrier mobility may indicate that violet-P₁₁ is a good candidate for next-generation electronics and optoelectronics.

ASSOCIATED CONTENT

Supporting Information

The Supporting Information is available free of charge at <https://pubs.acs.org/doi/10.1021/jacs.3c01766>.

Refined crystallographic data, SEM images, EDS results, PXRD results, additional PL and Raman results, additional cross-sectional STEM, air exposure-dependent PL, HAADF STEM images, AFM results, optical micrographs, SEM images, additional DFT calculation results, and crystal photos ([PDF](#))

Accession Codes

CCDC 2208167 contains the supplementary crystallographic data for this paper. These data can be obtained free of charge via www.ccdc.cam.ac.uk/data_request/cif, or by emailing data_request@ccdc.cam.ac.uk, or by contacting The Cambridge Crystallographic Data Centre, 12 Union Road, Cambridge CB2 1EZ, UK; fax: +44 1223 336033.

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Notes

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